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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	196
Number of Logic Elements/Cells	466
Total RAM Bits	6272
Number of I/O	61
Number of Gates	10000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs10-3pc84c

General Overview

Spartan series FPGAs are implemented with a regular, flexible, programmable architecture of Configurable Logic Blocks (CLBs), interconnected by a powerful hierarchy of versatile routing resources (routing channels), and surrounded by a perimeter of programmable Input/Output Blocks (IOBs), as seen in Figure 1. They have generous routing resources to accommodate the most complex interconnect patterns.

The devices are customized by loading configuration data into internal static memory cells. Re-programming is possible an unlimited number of times. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA. The FPGA can either actively read its configuration data from an external serial PROM (Master Serial mode), or the configuration data can be written into the FPGA from an external device (Slave Serial mode).

Spartan series FPGAs can be used where hardware must be adapted to different user applications. FPGAs are ideal for shortening design and development cycles, and also offer a cost-effective solution for production rates well beyond 50,000 systems per month.

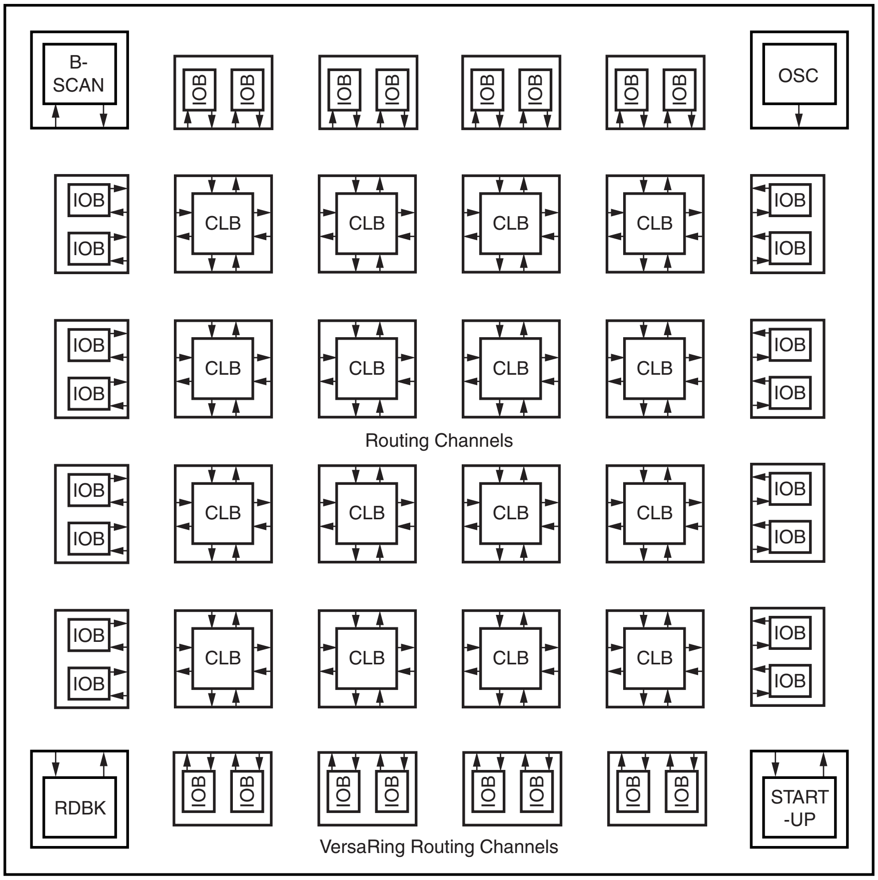

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Figure 1: **Basic FPGA Block Diagram**

Output Multiplexer/2-Input Function Generator (Spartan-XL Family Only)

The output path in the Spartan-XL family IOB contains an additional multiplexer not available in the Spartan family IOB. The multiplexer can also be configured as a 2-input function generator, implementing a pass gate, AND gate, OR gate, or XOR gate, with 0, 1, or 2 inverted inputs.

When configured as a multiplexer, this feature allows two output signals to time-share the same output pad, effectively doubling the number of device outputs without requiring a larger, more expensive package. The select input is the pin used for the output flip-flop clock, OK.

When the multiplexer is configured as a 2-input function generator, logic can be implemented within the IOB itself. Combined with a Global buffer, this arrangement allows very high-speed gating of a single signal. For example, a wide decoder can be implemented in CLBs, and its output gated with a Read or Write Strobe driven by a global buffer.

The user can specify that the IOB function generator be used by placing special library symbols beginning with the letter "O." For example, a 2-input AND gate in the IOB function generator is called OAND2. Use the symbol input pin labeled "F" for the signal on the critical path. This signal is placed on the OK pin — the IOB input with the shortest delay to the function generator. Two examples are shown in Figure 7.

Figure 7: **AND and MUX Symbols in Spartan-XL IOB**

Output Buffer

An active High 3-state signal can be used to place the output buffer in a high-impedance state, implementing 3-state outputs or bidirectional I/O. Under configuration control, the output (O) and output 3-state (T) signals can be inverted. The polarity of these signals is independently configured for each IOB (see Figure 6, page 7). An output can be configured as open-drain (open-collector) by tying the 3-state pin (T) to the output signal, and the input pin (I) to Ground.

By default, a 5V Spartan device output buffer pull-up structure is configured as a TTL-like totem-pole. The High driver is an n-channel pull-up transistor, pulling to a voltage one transistor threshold below V_{CC}. Alternatively, the outputs can be globally configured as CMOS drivers, with additional p-channel pull-up transistors pulling to V_{CC}. This option, applied using the bitstream generation software, applies to all outputs on the device. It is not individually programmable.

All Spartan-XL device outputs are configured as CMOS drivers, therefore driving rail-to-rail. The Spartan-XL family outputs are individually programmable for 12 mA or 24 mA output drive.

Any 5V Spartan device with its outputs configured in TTL mode can drive the inputs of any typical 3.3V device. Supported destinations for Spartan/XL device outputs are shown in Table 7.

Three-State Register (Spartan-XL Family Only)

Spartan-XL devices incorporate an optional register controlling the three-state enable in the IOBs. The use of the three-state control register can significantly improve output enable and disable time.

Output Slew Rate

The slew rate of each output buffer is, by default, reduced, to minimize power bus transients when switching non-critical signals. For critical signals, attach a FAST attribute or property to the output buffer or flip-flop.

Spartan/XL devices have a feature called "Soft Start-up," designed to reduce ground bounce when all outputs are turned on simultaneously at the end of configuration. When the configuration process is finished and the device starts up, the first activation of the outputs is automatically slew-rate limited. Immediately following the initial activation of the I/O, the slew rate of the individual outputs is determined by the individual configuration option for each IOB.

Pull-up and Pull-down Network

Programmable pull-up and pull-down resistors are used for tying unused pins to V_{CC} or Ground to minimize power consumption and reduce noise sensitivity. The configurable pull-up resistor is a p-channel transistor that pulls to V_{CC}. The configurable pull-down resistor is an n-channel transistor that pulls to Ground. The value of these resistors is typically 20 KΩ – 100 KΩ (See "Spartan Family DC Characteristics Over Operating Conditions" on page 43.).

This high value makes them unsuitable as wired-AND pull-up resistors.

Table 7: **Supported Destinations for Spartan/XL Outputs**

Destination	Spartan-XL Outputs	Spartan Outputs	
	3.3V, CMOS	5V, TTL	5V, CMOS
Any device, V_{CC} = 3.3V, CMOS-threshold inputs	√	√	Some(1)
Any device, V_{CC} = 5V, TTL-threshold inputs	√	√	√
Any device, V_{CC} = 5V, CMOS-threshold inputs	Unreliable Data		√

Notes:

1. Only if destination device has 5V tolerant inputs.

After configuration, voltage levels of unused pads, bonded or unbonded, must be valid logic levels, to reduce noise sensitivity and avoid excess current. Therefore, by default, unused pads are configured with the internal pull-up resistor active. Alternatively, they can be individually configured with the pull-down resistor, or as a driven output, or to be driven by an external source. To activate the internal pull-up, attach the PULLUP library component to the net attached to the pad. To activate the internal pull-down, attach the PULLDOWN library component to the net attached to the pad.

Set/Reset

As with the CLB registers, the GSR signal can be used to set or clear the input and output registers, depending on the value of the INIT attribute or property. The two flip-flops can be individually configured to set or clear on reset and after configuration. Other than the global GSR net, no user-controlled set/reset signal is available to the I/O flip-flops (Figure 5). The choice of set or reset applies to both the initial state of the flip-flop and the response to the GSR pulse.

Independent Clocks

Separate clock signals are provided for the input (IK) and output (OK) flip-flops. The clock can be independently inverted for each flip-flop within the IOB, generating either falling-edge or rising-edge triggered flip-flops. The clock inputs for each IOB are independent.

Common Clock Enables

The input and output flip-flops in each IOB have a common clock enable input (see EC signal in Figure 5), which through configuration, can be activated individually for the input or output flip-flop, or both. This clock enable operates exactly like the EC signal on the Spartan/XL FPGA CLB. It cannot be inverted within the IOB.

Routing Channel Description

All internal routing channels are composed of metal segments with programmable switching points and switching matrices to implement the desired routing. A structured, hierarchical matrix of routing channels is provided to achieve efficient automated routing.

This section describes the routing channels available in Spartan/XL devices. Figure 8 shows a general block diagram of the CLB routing channels. The implementation software automatically assigns the appropriate resources based on the density and timing requirements of the design. The following description of the routing channels is for information only and is simplified with some minor details omitted. For an exact interconnect description the designer should open a design in the FPGA Editor and review the actual connections in this tool.

The routing channels will be discussed as follows;

- CLB routing channels which run along each row and column of the CLB array.
- IOB routing channels which form a ring (called a VersaRing) around the outside of the CLB array. It connects the I/O with the CLB routing channels.
- Global routing consists of dedicated networks primarily designed to distribute clocks throughout the device with minimum delay and skew. Global routing can also be used for other high-fanout signals.

CLB Routing Channels

The routing channels around the CLB are derived from three types of interconnects; single-length, double-length, and longlines. At the intersection of each vertical and horizontal routing channel is a signal steering matrix called a Programmable Switch Matrix (PSM). Figure 8 shows the basic routing channel configuration showing single-length lines, double-length lines and longlines as well as the CLBs and PSMs. The CLB to routing channel interface is shown as well as how the PSMs interface at the channel intersections.

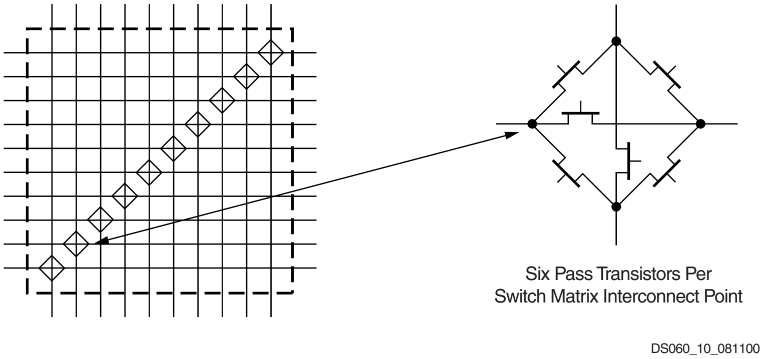


Figure 10: **Programmable Switch Matrix**

Double-Length Lines

The double-length lines consist of a grid of metal segments, each twice as long as the single-length lines: they run past two CLBs before entering a PSM. Double-length lines are grouped in pairs with the PSMs staggered, so that each line goes through a PSM at every other row or column of CLBs (see Figure 8).

There are four vertical and four horizontal double-length lines associated with each CLB. These lines provide faster signal routing over intermediate distances, while retaining routing flexibility.

Longlines

Longlines form a grid of metal interconnect segments that run the entire length or width of the array. Longlines are intended for high fan-out, time-critical signal nets, or nets that are distributed over long distances.

Each Spartan/XL device longline has a programmable splitter switch at its center. This switch can separate the line into two independent routing channels, each running half the width or height of the array.

Routing connectivity of the longlines is shown in Figure 8. The longlines also interface to some 3-state buffers which is described later in **3-State Long Line Drivers**, page 19.

I/O Routing

Spartan/XL devices have additional routing around the IOB ring. This routing is called a VersaRing. The VersaRing facilitates pin-swapping and redesign without affecting board layout. Included are eight double-length lines, and four longlines.

Global Nets and Buffers

The Spartan/XL devices have dedicated global networks. These networks are designed to distribute clocks and other high fanout control signals throughout the devices with minimal skew.

Four vertical longlines in each CLB column are driven exclusively by special global buffers. These longlines are in addition to the vertical longlines used for standard interconnect. In the 5V Spartan devices, the four global lines can be driven by either of two types of global buffers; Primary Global buffers (BUFGP) or Secondary Global buffers (BUFGS). Each of these lines can be accessed by one particular Primary Global buffer, or by any of the Secondary Global buffers, as shown in Figure 11. In the 3V Spartan-XL devices, the four global lines can be driven by any of the eight Global Low-Skew Buffers (BUFGLS). The clock pins of every CLB and IOB can also be sourced from local interconnect.

CLB signals from which they are originally derived are shown in Table 10.

Table 10: **Dual-Port RAM Signals**

RAM Signal	Function	CLB Signal
D	Data In	DIN
A[3:0]	Read Address for Single-Port. Write Address for Single-Port and Dual-Port.	F[4:1]
DPRA[3:0]	Read Address for Dual-Port	G[4:1]
WE	Write Enable	SR
WCLK	Clock	K
SPO	Single Port Out (addressed by A[3:0])	F_{OUT}
DPO	Dual Port Out (addressed by DPRA[3:0])	G_{OUT}

The RAM16X1D primitive used to instantiate the dual-port RAM consists of an upper and a lower 16 x 1 memory array. The address port labeled A[3:0] supplies both the read and write addresses for the lower memory array, which behaves the same as the 16 x 1 single-port RAM array described previously. Single Port Out (SPO) serves as the data output for the lower memory. Therefore, SPO reflects the data at address A[3:0].

The other address port, labeled DPRA[3:0] for Dual Port Read Address, supplies the read address for the upper memory. The write address for this memory, however, comes from the address A[3:0]. Dual Port Out (DPO) serves as the data output for the upper memory. Therefore, DPO reflects the data at address DPRA[3:0].

By using A[3:0] for the write address and DPRA[3:0] for the read address, and reading only the DPO output, a FIFO that can read and write simultaneously is easily generated. The simultaneous read/write capability possible with the dual-port RAM can provide twice the effective data throughput of a single-port RAM alternating read and write operations.

The timing relationships for the dual-port RAM mode are shown in Figure 13.

Note that write operations to RAM are synchronous (edge-triggered); however, data access is asynchronous.

Initializing RAM at FPGA Configuration

Both RAM and ROM implementations in the Spartan/XL families are initialized during device configuration. The initial contents are defined via an INIT attribute or property attached to the RAM or ROM symbol, as described in the library guide. If not defined, all RAM contents are initialized to zeros, by default.

RAM initialization occurs only during device configuration. The RAM content is not affected by GSR.

More Information on Using RAM Inside CLBs

Three application notes are available from Xilinx that discuss synchronous (edge-triggered) RAM: *"Xilinx Edge-Triggered and Dual-Port RAM Capability," "Implementing FIFOs in Xilinx RAM,"* and *"Synchronous and Asynchronous FIFO Designs."* All three application notes apply to both the Spartan and the Spartan-XL families.

Fast Carry Logic

Each CLB F-LUT and G-LUT contains dedicated arithmetic logic for the fast generation of carry and borrow signals. This extra output is passed on to the function generator in the adjacent CLB. The carry chain is independent of normal routing resources. (See Figure 15.)

Dedicated fast carry logic greatly increases the efficiency and performance of adders, subtractors, accumulators, comparators and counters. It also opens the door to many new applications involving arithmetic operation, where the previous generations of FPGAs were not fast enough or too inefficient. High-speed address offset calculations in microprocessor or graphics systems, and high-speed addition in digital signal processing are two typical applications.

The two 4-input function generators can be configured as a 2-bit adder with built-in hidden carry that can be expanded to any length. This dedicated carry circuitry is so fast and efficient that conventional speed-up methods like carry generate/propagate are meaningless even at the 16-bit level, and of marginal benefit at the 32-bit level. This fast carry logic is one of the more significant features of the Spartan

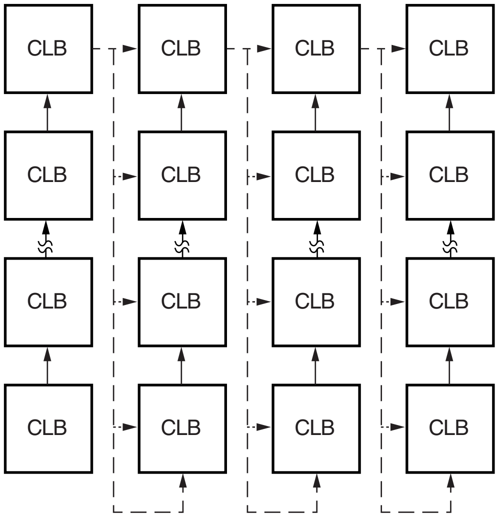


Figure 15: **Available Spartan/XL Carry Propagation Paths**

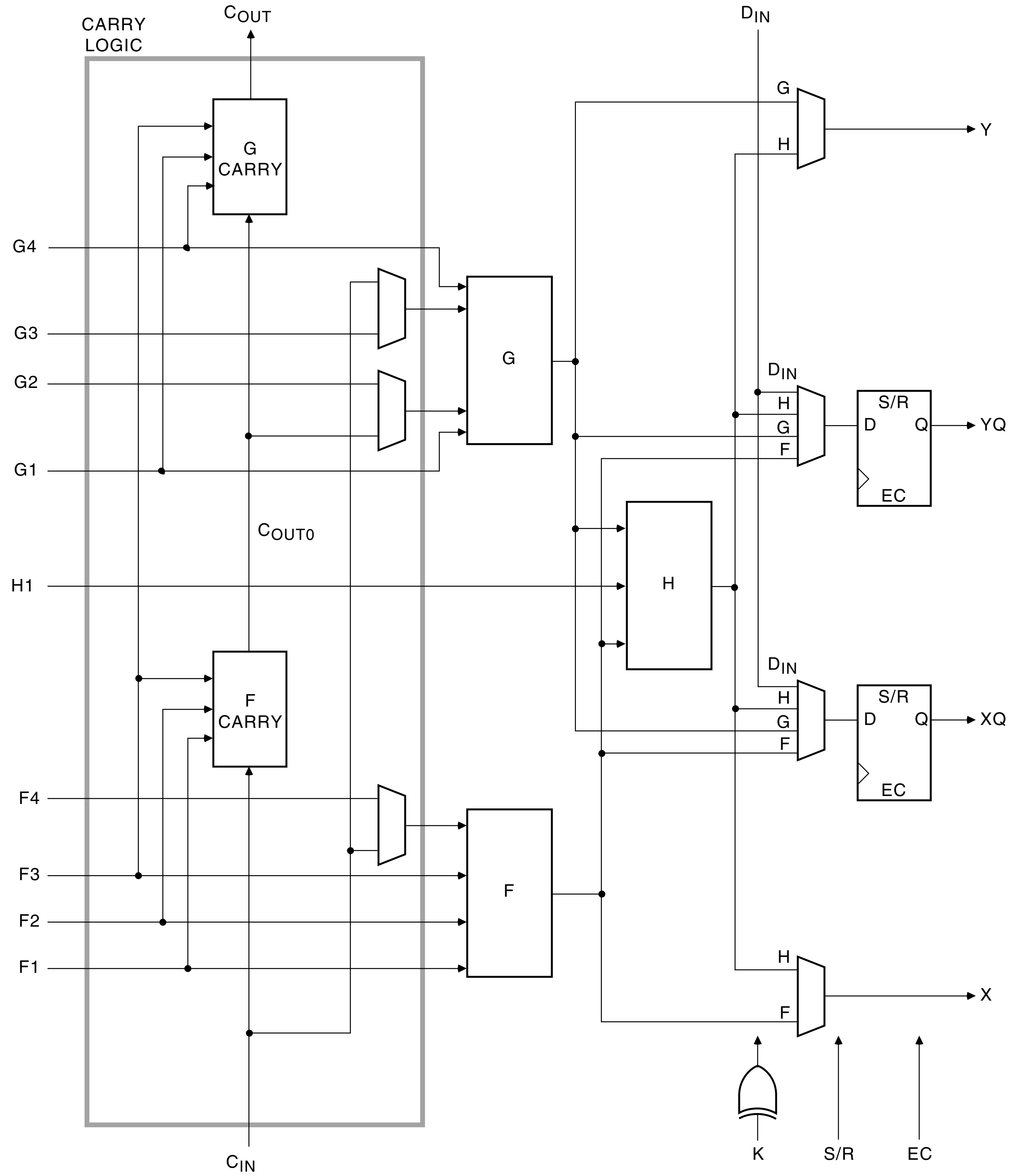
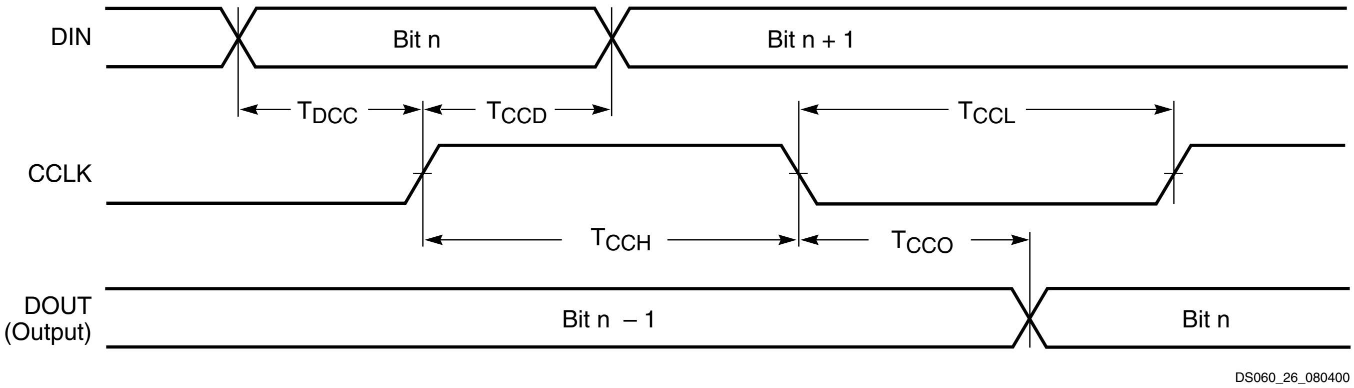


Figure 16: **Fast Carry Logic in Spartan/XL CLB**



Symbol		Description	Min	Max	Units
T_{DCC}	CCLK	DIN setup	20	-	ns
T_{CCD}		DIN hold	0	-	ns
T_{CCO}		DIN to DOUT	-	30	ns
T_{CCH}		High time	40	-	ns
T_{CCL}		Low time	40	-	ns
F_{CC}		Frequency	-	12.5	MHz

Notes:
1. Configuration must be delayed until the $\overline{\text{INIT}}$ pins of all daisy-chained FPGAs are High.

Figure 26: **Slave Serial Mode Programming Switching Characteristics**

Express Mode (Spartan-XL Family Only)

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers (Figure 27). A CCLK frequency of 1 MHz is equivalent to a 8 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking. A length count is not used in Express mode.

Express mode must be specified as an option to the development system. The Express mode bitstream is not compatible with the other configuration modes (see Table 16, page 32.) Express mode is selected by a <0X> on the Mode pins (M1, M0).

The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge (Figure 28).

Pseudo Daisy Chain

Multiple devices with different configurations can be configured in a pseudo daisy chain provided that all of the devices are in Express mode. Concatenated bitstreams are used to configure the chain of Express mode devices so that each device receives a separate header. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. Frame data is accepted only when CS1 is High and the device's configuration memory is not already full. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pull-up). The status pin DOUT is pulled Low after the header is received, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the next header and configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using a development system option.

The requirement that all DONE pins in a daisy chain be wired together applies only to Express mode, and only if all devices in the chain are to become active simultaneously. All Spartan-XL devices in Express mode are synchronized

Readback Switching Characteristics Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions.

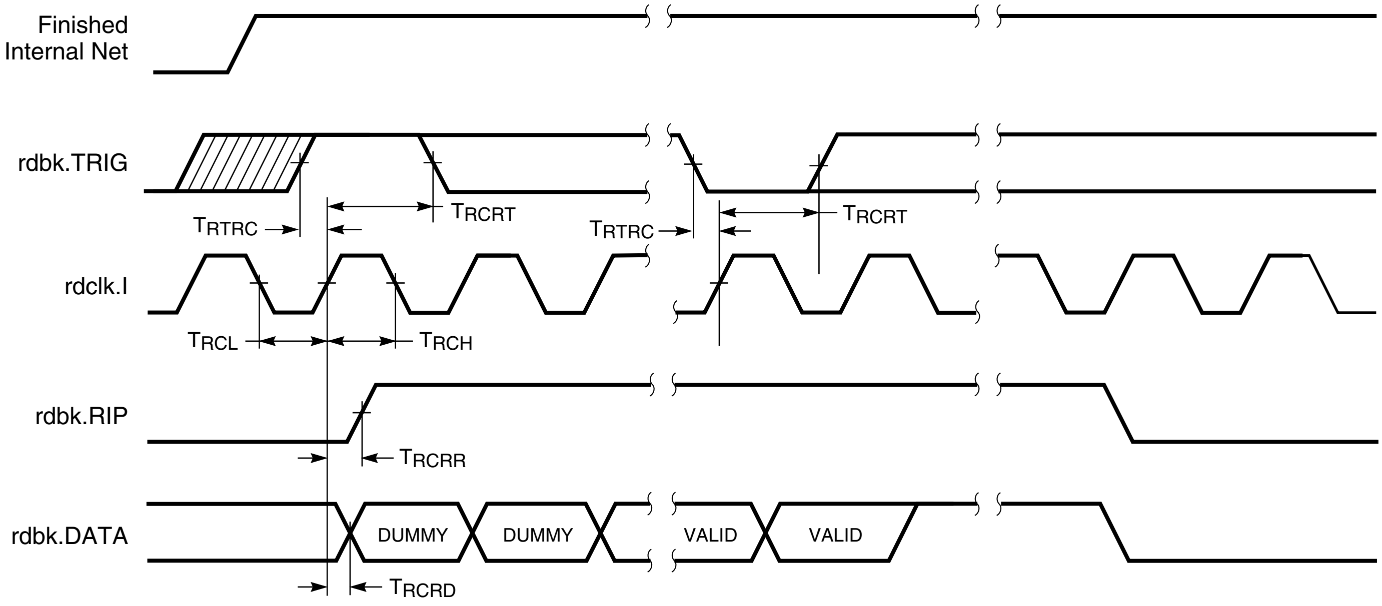


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Figure 33: **Spartan and Spartan-XL Readback Timing Diagram**

Spartan and Spartan-XL Readback Switching Characteristics

Symbol		Description	Min	Max	Units
T$_{RTRC}$	rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	200	-	ns
T$_{RCRT}$		rdbk.TRIG hold to initiate and abort Readback	50	-	ns
T$_{RCRD}$	rdclk.I	rdbk.DATA delay	-	250	ns
T$_{RCRR}$		rdbk.RIP delay	-	250	ns
T$_{RCH}$		High time	250	500	ns
T$_{RCL}$		Low time	250	500	ns

Notes:

1. Timing parameters apply to all speed grades.
2. If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.

Spartan Family DC Characteristics Over Operating Conditions

Symbol	Description		Min	Max	Units
V_{OH}	High-level output voltage @ $I_{OH} = -4.0$ mA, V_{CC} min	TTL outputs	2.4	-	V
	High-level output voltage @ $I_{OH} = -1.0$ mA, V_{CC} min	CMOS outputs	$V_{CC} - 0.5$	-	V
V_{OL}	Low-level output voltage @ I_{OL} = 12.0 mA, V_{CC} min(1)	TTL outputs	-	0.4	V
		CMOS outputs	-	0.4	V
V_{DR}	Data retention supply voltage (below which configuration data may be lost)		3.0	-	V
I_{CCO}	Quiescent FPGA supply current(2)	Commercial	-	3.0	mA
		Industrial	-	6.0	mA
I_L	Input or output leakage current		–10	+10	µA
C_{IN}	Input capacitance (sample tested)		-	10	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V (sample tested)		0.02	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 5V (sample tested)		0.02	-	mA

Notes:
1. With 50% of the outputs simultaneously sinking 12 mA, up to a maximum of 64 pins.
2. With no output current loads, no active input pull-up resistors, all package pins at V_{CC} or GND, and the FPGA configured with a Tie option.

Spartan Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -4 Max	Speed Grade -3 Max	Units
T_{PG}	From pad through Primary buffer, to any clock K	XCS05	2.0	4.0	ns
		XCS10	2.4	4.3	ns
		XCS20	2.8	5.4	ns
		XCS30	3.2	5.8	ns
		XCS40	3.5	6.4	ns
T_{SG}	From pad through Secondary buffer, to any clock K	XCS05	2.5	4.4	ns
		XCS10	2.9	4.7	ns
		XCS20	3.3	5.8	ns
		XCS30	3.6	6.2	ns
		XCS40	3.9	6.7	ns

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines (continued)

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and are expressed in nanoseconds unless otherwise noted.

Dual-Port RAM Synchronous (Edge-Triggered) Write Operation Characteristics

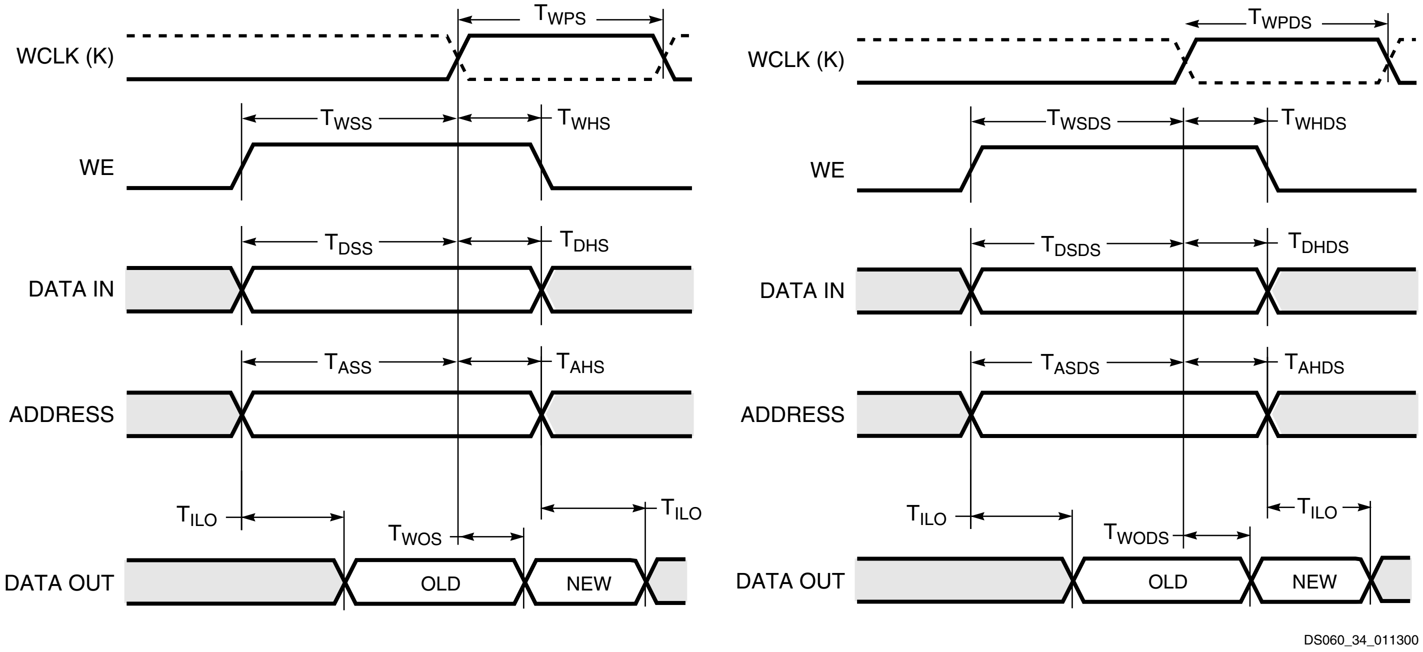
Symbol	Dual Port RAM	Size[1]	-4		-3		Units
			Min	Max	Min	Max	
Write Operation							
T_{WCDS}	Address write cycle time (clock K period)	16x1	8.0	-	11.6	-	ns
T_{WPDS}	Clock K pulse width (active edge)	16x1	4.0	-	5.8	-	ns
T_{ASDS}	Address setup time before clock K	16x1	1.5	-	2.1	-	ns
T_{AHDS}	Address hold time after clock K	16x1	0	-	0	-	ns
T_{DSDS}	DIN setup time before clock K	16x1	1.5	-	1.6	-	ns
T_{DHDS}	DIN hold time after clock K	16x1	0	-	0	-	ns
T_{WSDS}	WE setup time before clock K	16x1	1.5	-	1.6	-	ns
T_{WHDS}	WE hold time after clock K	16x1	0	-	0	-	ns
T_{WODS}	Data valid after clock K	16x1	-	6.5	-	7.0	ns

Notes:

1. Read Operation timing for 16 x 1 dual-port RAM option is identical to 16 x 2 single-port RAM timing

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Timing

Single Port **Dual Port**



Spartan Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report.

Spartan Family Output Flip-Flop, Clock-to-Out

Symbol	Description	Device	Speed Grade -4 Max	Speed Grade -3 Max	Units
Global Primary Clock to TTL Output using OFF					
T_{ICKOF}	Fast	XCS05	5.3	8.7	ns
		XCS10	5.7	9.1	ns
		XCS20	6.1	9.3	ns
		XCS30	6.5	9.4	ns
		XCS40	6.8	10.2	ns
T_{ICKO}	Slew-rate limited	XCS05	9.0	11.5	ns
		XCS10	9.4	12.0	ns
		XCS20	9.8	12.2	ns
		XCS30	10.2	12.8	ns
		XCS40	10.5	12.8	ns
Global Secondary Clock to TTL Output using OFF					
T_{ICKSOF}	Fast	XCS05	5.8	9.2	ns
		XCS10	6.2	9.6	ns
		XCS20	6.6	9.8	ns
		XCS30	7.0	9.9	ns
		XCS40	7.3	10.7	ns
T_{ICKSO}	Slew-rate limited	XCS05	9.5	12.0	ns
		XCS10	9.9	12.5	ns
		XCS20	10.3	12.7	ns
		XCS30	10.7	13.2	ns
		XCS40	11.0	14.3	ns
Delay Adder for CMOS Outputs Option					
T_{CMOSOF}	Fast	All devices	0.8	1.0	ns
T_{CMOSO}	Slew-rate limited	All devices	1.5	2.0	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column,and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load. For different loads, see Figure 34.
3. OFF = Output Flip-Flop

Spartan-XL Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and expressed in nanoseconds unless otherwise noted.

Symbol	Description	Speed Grade				Units
		-5		-4		
		Min	Max	Min	Max	
Clocks						
T_{CH}	Clock High time	2.0	-	2.3	-	ns
T_{CL}	Clock Low time	2.0	-	2.3	-	ns
Combinatorial Delays						
T_{ILO}	F/G inputs to X/Y outputs	-	1.0	-	1.1	ns
T_{IHO}	F/G inputs via H to X/Y outputs	-	1.7	-	2.0	ns
T_{ITO}	F/G inputs via transparent latch to Q outputs	-	1.5	-	1.8	ns
T_{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.5	-	1.8	ns
Sequential Delays						
T_{CKO}	Clock K to Flip-Flop or latch outputs Q	-	1.2	-	1.4	ns
Setup Time before Clock K						
T_{ICK}	F/G inputs	0.6	-	0.7	-	ns
T_{IHCK}	F/G inputs via H	1.3	-	1.6	-	ns
Hold Time after Clock K						
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset Direct						
T_{RPW}	Width (High)	2.5	-	2.8	-	ns
T_{RIO}	Delay from C inputs via S/R, going High to Q	-	2.3	-	2.7	ns
Global Set/Reset						
T_{MRW}	Minimum GSR Pulse Width	10.5	-	11.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See page 60 for T_{RRI} values per device.				
F_{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	250	-	217	MHz

Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Single Port RAM	Size[1]	Speed Grade -5 Min	Speed Grade -5 Max	Speed Grade -4 Min	Speed Grade -4 Max	Units
Write Operation							
T_{WCS}	Address write cycle time (clock K period)	16x2	7.7	-	8.4	-	ns
T_{WCTS}		32x1	7.7	-	8.4	-	ns
T_{WPS}	Clock K pulse width (active edge)	16x2	3.1	-	3.6	-	ns
T_{WPTS}		32x1	3.1	-	3.6	-	ns
T_{ASS}	Address setup time before clock K	16x2	1.3	-	1.5	-	ns
T_{ASTS}		32x1	1.5	-	1.7	-	ns
T_{DSS}	DIN setup time before clock K	16x2	1.5	-	1.7	-	ns
T_{DSTS}		32x1	1.8	-	2.1	-	ns
T_{WSS}	WE setup time before clock K	16x2	1.4	-	1.6	-	ns
T_{WSTS}		32x1	1.3	-	1.5	-	ns
	All hold times after clock K	16x2	0.0	-	0.0	-	ns
T_{WOS}	Data valid after clock K	32x1	-	4.5	-	5.3	ns
T_{WOTS}		16x2	-	5.4	-	6.3	ns
Read Operation							
T_{RC}	Address read cycle time	16x2	2.6	-	3.1	-	ns
T_{RCT}		32x1	3.8	-	5.5	-	ns
T_{ILO}	Data Valid after address change (no Write Enable)	16x2	-	1.0	-	1.1	ns
T_{IHO}		32x1	-	1.7	-	2.0	ns
T_{ICK}	Address setup time before clock K	16x2	0.6	-	0.7	-	ns
T_{IHCK}		32x1	1.3	-	1.6	-	ns

Notes:

1. Timing for 16 x 1 RAM option is identical to 16 x 2 RAM timing.

Spartan-XL Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan-XL Family Output Flip-Flop, Clock-to-Out

Symbol	Description	Device	Speed Grade		Units
			-5	-4	
			Max	Max	
Global Clock to Output using OFF					
T_{ICKOF}	Fast	XCS05XL	4.6	5.2	ns
		XCS10XL	4.9	5.5	ns
		XCS20XL	5.2	5.8	ns
		XCS30XL	5.5	6.2	ns
		XCS40XL	5.8	6.5	ns
Slew Rate Adjustment					
T_{SLOW}	For Output SLOW option add	All Devices	1.5	1.7	ns

Notes:

1. Output delays are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load.
3. OFF = Output Flip Flop

Spartan-XL Family Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan-XL Family Setup and Hold

Symbol	Description	Device	Speed Grade		Units
			-5	-4	
			Max	Max	
Input Setup/Hold Times Using Global Clock and IFF					
T_{SUF}/T_{HF}	No Delay	XCS05XL	1.1/2.0	1.6/2.6	ns
		XCS10XL	1.0/2.2	1.5/2.8	ns
		XCS20XL	0.9/2.4	1.4/3.0	ns
		XCS30XL	0.8/2.6	1.3/3.2	ns
		XCS40XL	0.7/2.8	1.2/3.4	ns
T_{SU}/T_{H}	Full Delay	XCS05XL	3.9/0.0	5.1/0.0	ns
		XCS10XL	4.1/0.0	5.3/0.0	ns
		XCS20XL	4.3/0.0	5.5/0.0	ns
		XCS30XL	4.5/0.0	5.7/0.0	ns
		XCS40XL	4.7/0.0	5.9/0.0	ns

Notes:

1. IFF = Input Flip-Flop or Latch
2. Setup time is measured with the fastest route and the lightest load. Hold time is measured using the furthest distance and a reference load of one clock pin per IOB/CLB.

Capacitive Load Factor

Figure 35 shows the relationship between I/O output delay and load capacitance. It allows a user to adjust the specified output delay if the load capacitance is different than 50 pF. For example, if the actual load capacitance is 120 pF, add 2.5 ns to the specified delay. If the load capacitance is 20 pF, subtract 0.8 ns from the specified output delay. Figure 35 is usable over the specified operating conditions of voltage and temperature and is independent of the output slew rate control.

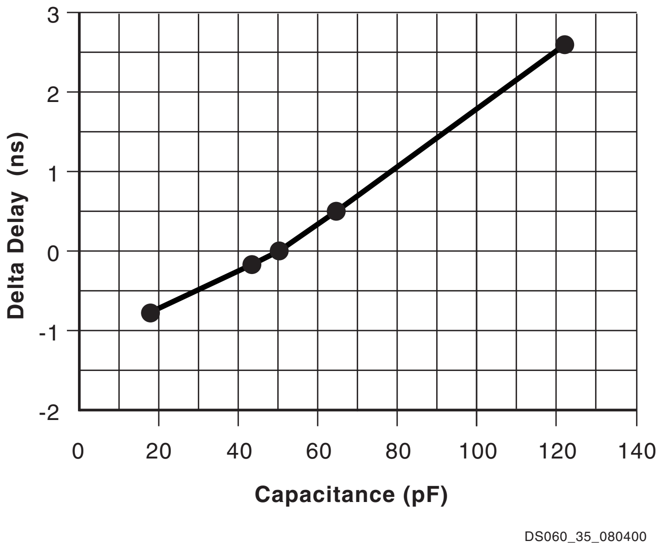


Figure 35: **Delay Factor at Various Capacitive Loads**

Spartan-XL Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -5 Min	Speed Grade -5 Max	Speed Grade -4 Min	Speed Grade -4 Max	Units
Setup Times							
T_{ECIK}	Clock Enable (EC) to Clock (IK)	All devices	0.0	-	0.0	-	ns
T_{PICK}	Pad to Clock (IK), no delay	All devices	1.0	-	1.2	-	ns
T_{POCK}	Pad to Fast Capture Latch Enable (OK), no delay	All devices	0.7	-	0.8	-	ns
Hold Times							
	All Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays							
T_{PID}	Pad to I1, I2	All devices	-	0.9	-	1.1	ns
T_{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.1	-	2.5	ns
T_{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	1.0	-	1.1	ns
T_{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	1.1	-	1.2	ns
Delay Adder for Input with Full Delay Option							
T_{Delay}	$T_{PICKD} = T_{PICK} + T_{Delay}$ $T_{PDLI} = T_{PLI} + T_{Delay}$	XCS05XL	4.0	-	4.7	-	ns
		XCS10XL	4.8	-	5.6	-	ns
		XCS20XL	5.0	-	5.9	-	ns
		XCS30XL	5.5	-	6.5	-	ns
		XCS40XL	6.5	-	7.6	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T_{RRI}	Delay from GSR input to any Q	XCS05XL	-	9.0	-	10.5	ns
		XCS10XL	-	9.5	-	11.0	ns
		XCS20XL	-	10.0	-	11.5	ns
		XCS30XL	-	11.0	-	12.5	ns
		XCS40XL	-	12.0	-	13.5	ns

Notes:

1. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
2. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan-XL Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade				Units
			-5		-4		
			Min	Max	Min	Max	
Propagation Delays							
T_{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.2	-	3.7	ns
T_{OPF}	Output (O) to Pad, fast	All devices	-	2.5	-	2.9	ns
T_{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	2.8	-	3.3	ns
T_{TSONF}	3-state to Pad active and valid, fast	All devices	-	2.6	-	3.0	ns
T_{OFPF}	Output (O) to Pad via Output MUX, fast	All devices	-	3.7	-	4.4	ns
T_{OKFPF}	Select (OK) to Pad via Output MUX, fast	All devices	-	3.3	-	3.9	ns
T_{SLOW}	For Output SLOW option add	All devices	-	1.5	-	1.7	ns
Setup and Hold Times							
T_{OOK}	Output (O) to clock (OK) setup time	All devices	0.5	-	0.5	-	ns
T_{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T_{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	0.0	-	0.0	-	ns
T_{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.1	-	0.2	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T_{RPO}	Delay from GSR input to any Pad	XCS05XL	-	11.9	-	14.0	ns
		XCS10XL	-	12.4	-	14.5	ns
		XCS20XL	-	12.9	-	15.0	ns
		XCS30XL	-	13.9	-	16.0	ns
		XCS40XL	-	14.9	-	17.0	ns

Notes:

1. Output timing is measured at ~50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
2. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Table 18: **Pin Descriptions *(Continued)***

Pin Name	I/O During Config.	I/O After Config.	Pin Description
SGCK1 - SGCK4 (Spartan)	Weak Pull-up (except SGCK4 is DOUT)	I or I/O	Four Secondary Global inputs each drive a dedicated internal global net with short delay and minimal skew. These internal global nets can also be driven from internal logic. If not used to drive a global net, any of these pins is a user-programmable I/O pin. The SGCK1-SGCK4 pins provide the shortest path to the four Secondary Global Buffers. Any input pad symbol connected directly to the input of a BUFGS symbol is automatically placed on one of these pins.
GCK1 - GCK8 (Spartan-XL)	Weak Pull-up (except GCK6 is DOUT)	I or I/O	Eight Global inputs each drive a dedicated internal global net with short delay and minimal skew. These internal global nets can also be driven from internal logic. If not used to drive a global net, any of these pins is a user-programmable I/O pin. The GCK1-GCK8 pins provide the shortest path to the eight Global Low-Skew Buffers. Any input pad symbol connected directly to the input of a BUFGLS symbol is automatically placed on one of these pins.
CS1 (Spartan-XL)	I	I/O	During Express configuration, CS1 is used as a serial-enable signal for daisy-chaining.
D0-D7 (Spartan-XL)	I	I/O	During Express configuration, these eight input pins receive configuration data. After configuration, they are user-programmable I/O pins.
DIN	I	I/O	During Slave Serial or Master Serial configuration, DIN is the serial configuration data input receiving data on the rising edge of CCLK. After configuration, DIN is a user-programmable I/O pin.
DOUT	O	I/O	During Slave Serial or Master Serial configuration, DOUT is the serial configuration data output that can drive the DIN of daisy-chained slave FPGAs. DOUT data changes on the falling edge of CCLK, one-and-a-half CCLK periods after it was received at the DIN input. In Spartan-XL family Express mode, DOUT is the status output that can drive the CS1 of daisy-chained FPGAs, to enable and disable downstream devices. After configuration, DOUT is a user-programmable I/O pin.
Unrestricted User-Programmable I/O Pins			
I/O	Weak Pull-up	I/O	These pins can be configured to be input and/or output after configuration is completed. Before configuration is completed, these pins have an internal high-value pull-up resistor network that defines the logic level as High.

XCS05 and XCS05XL Device Pinouts

XCS05/XL Pad Name	PC84(4)	VQ100	Bndry Scan
I/O	P70	P71	238(3)
I/O (D0(2), DIN)	P71	P72	241(3)
I/O, SGCK4(1), GCK6(2) (DOUT)	P72	P73	244(3)
CCLK	P73	P74	-
VCC	P74	P75	-
O, TDO	P75	P76	0
GND	P76	P77	-
I/O	P77	P78	2
I/O, PGCK4(1), GCK7(2)	P78	P79	5
I/O (CS1(2))	P79	P80	8
I/O	P80	P81	11
I/O	P81	P82	14
I/O	P82	P83	17
I/O	-	P84	20
I/O	-	P85	23
I/O	P83	P86	26
I/O	P84	P87	29
GND	P1	P88	-

Notes:

1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS05XL is not part of the Boundary Scan chain. For the XCS05XL, subtract 1 from all Boundary Scan numbers from GCK3 on (127 and higher).
4. PC84 package discontinued by PDN2004-01

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84(4)	VQ100	CS144(2,4)	TQ144	Bndry Scan
VCC	P2	P89	D7	P128	-
I/O	P3	P90	A6	P129	44
I/O	P4	P91	B6	P130	47
I/O	-	P92	C6	P131	50
I/O	-	P93	D6	P132	53
I/O	P5	P94	A5	P133	56
I/O	P6	P95	B5	P134	59
I/O	-	-	C5	P135	62
I/O	-	-	D5	P136	65
GND	-	-	A4	P137	-
I/O	P7	P96	B4	P138	68
I/O	P8	P97	C4	P139	71
I/O	-	-	A3	P140	74
I/O	-	-	B3	P141	77
I/O	P9	P98	C3	P142	80

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84(4)	VQ100	CS144(2,4)	TQ144	Bndry Scan
I/O, SGCK1(1) GCK8(2)	P10	P99	A2	P143	83
VCC	P11	P100	B2	P144	-
GND	P12	P1	A1	P1	-
I/O, PGCK1(1) GCK1(2)	P13	P2	B1	P2	86
I/O	P14	P3	C2	P3	89
I/O	-	-	C1	P4	92
I/O	-	-	D4	P5	95
I/O, TDI	P15	P4	D3	P6	98
I/O, TCK	P16	P5	D2	P7	101
GND	-	-	D1	P8	-
I/O	-	-	E4	P9	104
I/O	-	-	E3	P10	107
I/O, TMS	P17	P6	E2	P11	110
I/O	P18	P7	E1	P12	113
I/O	-	-	F4	P13	116
I/O	-	P8	F3	P14	119
I/O	P19	P9	F2	P15	122
I/O	P20	P10	F1	P16	125
GND	P21	P11	G2	P17	-
VCC	P22	P12	G1	P18	-
I/O	P23	P13	G3	P19	128
I/O	P24	P14	G4	P20	131
I/O	-	P15	H1	P21	134
I/O	-	-	H2	P22	137
I/O	P25	P16	H3	P23	140
I/O	P26	P17	H4	P24	143
I/O	-	-	J1	P25	146
I/O	-	-	J2	P26	149
GND	-	-	J3	P27	-
I/O	P27	P18	J4	P28	152
I/O	-	P19	K1	P29	155
I/O	-	-	K2	P30	158
I/O	-	-	K3	P31	161
I/O	P28	P20	L1	P32	164
I/O, SGCK2(1) GCK2(2)	P29	P21	L2	P33	167
Not Connected(1) M1(2)	P30	P22	L3	P34	170
GND	P31	P23	M1	P35	-
MODE(1), M0(2)	P32	P24	M2	P36	173

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144(2,4)	TQ144	PQ208	Bndry Scan
I/O	-	F4	P13	P21	170
I/O	P8	F3	P14	P22	173
I/O	P9	F2	P15	P23	176
I/O	P10	F1	P16	P24	179
GND	P11	G2	P17	P25	-
VCC	P12	G1	P18	P26	-
I/O	P13	G3	P19	P27	182
I/O	P14	G4	P20	P28	185
I/O	P15	H1	P21	P29	188
I/O	-	H2	P22	P30	191
I/O	-	-	-	P31	194
I/O	-	-	-	P32	197
VCC(2)	-	-	-	P33	-
I/O	P16	H3	P23	P34	200
I/O	P17	H4	P24	P35	203
I/O	-	J1	P25	P36	206
I/O	-	J2	P26	P37	209
GND	-	J3	P27	P38	-
I/O	-	-	-	P40	212
I/O	-	-	-	P41	215
I/O	-	-	-	P42	218
I/O	-	-	-	P43	221
I/O	P18	J4	P28	P44	224
I/O	P19	K1	P29	P45	227
I/O	-	K2	P30	P46	230
I/O	-	K3	P31	P47	233
I/O	P20	L1	P32	P48	236
I/O, SGCK2(1), GCK2(2)	P21	L2	P33	P49	239
Not Connected(1) M1(2)	P22	L3	P34	P50	242
GND	P23	M1	P35	P51	-
MODE(1), M0(2)	P24	M2	P36	P52	245
VCC	P25	N1	P37	P53	-
Not Connected(1) $\overline{\text{PWRDWN}}$(2)	P26	N2	P38	P54	246 (1)
I/O, PGCK2(1), GCK3(2)	P27	M3	P39	P55	247 (3)
I/O (HDC)	P28	N3	P40	P56	250 (3)
I/O	-	K4	P41	P57	253 (3)
I/O	-	L4	P42	P58	256 (3)
I/O	P29	M4	P43	P59	259 (3)

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144(2,4)	TQ144	PQ208	Bndry Scan
I/O ($\overline{\text{LDC}}$)	P30	N4	P44	P60	262 (3)
I/O	-	-	-	P61	265 (3)
I/O	-	-	-	P62	268 (3)
I/O	-	-	-	P63	271 (3)
I/O	-	-	-	P64	274 (3)
GND	-	K5	P45	P66	-
I/O	-	L5	P46	P67	277 (3)
I/O	-	M5	P47	P68	280 (3)
I/O	P31	N5	P48	P69	283 (3)
I/O	P32	K6	P49	P70	286 (3)
VCC(2)	-	-	-	P71	-
I/O	-	-	-	P72	289 (3)
I/O	-	-	-	P73	292 (3)
I/O	P33	L6	P50	P74	295 (3)
I/O	P34	M6	P51	P75	298 (3)
I/O	P35	N6	P52	P76	301 (3)
I/O ($\overline{\text{INIT}}$)	P36	M7	P53	P77	304 (3)
VCC	P37	N7	P54	P78	-
GND	P38	L7	P55	P79	-
I/O	P39	K7	P56	P80	307 (3)
I/O	P40	N8	P57	P81	310 (3)
I/O	P41	M8	P58	P82	313 (3)
I/O	P42	L8	P59	P83	316 (3)
I/O	-	-	-	P84	319 (3)
I/O	-	-	-	P85	322 (3)
VCC(2)	-	-	-	P86	-
I/O	P43	K8	P60	P87	325 (3)
I/O	P44	N9	P61	P88	328 (3)
I/O	-	M9	P62	P89	331 (3)
I/O	-	L9	P63	P90	334 (3)
GND	-	K9	P64	P91	-
I/O	-	-	-	P93	337 (3)
I/O	-	-	-	P94	340 (3)
I/O	-	-	-	P95	343 (3)
I/O	-	-	-	P96	346 (3)
I/O	P45	N10	P65	P97	349 (3)
I/O	P46	M10	P66	P98	352 (3)
I/O	-	L10	P67	P99	355 (3)
I/O	-	N11	P68	P100	358 (3)
I/O	P47	M11	P69	P101	361 (3)
I/O, SGCK3(1), GCK4(2)	P48	L11	P70	P102	364 (3)
GND	P49	N12	P71	P103	-
DONE	P50	M12	P72	P104	-
VCC	P51	N13	P73	P105	-